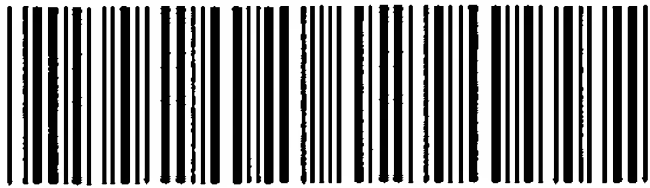


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/634,868	TOMITSUKA ET AL.	
	Examiner	Art Unit	
	Michael A. Friedhofer	2832	

SEARCHED			
Class	Subclass	Date	Examiner
200	5a,6a,511, 512,516, 517	3/18/2005	MAF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR